

BOUNDARY SCAN ANALYSISABSTRACT

A circuit testing approach involves the generation of boundary scan information using test vectors to identify characteristics of a circuit design and a boundary scan implementation therefor. According to an example embodiment of the present invention, test vectors are used in simulation to identify circuit design characteristics for establishing a boundary scan test program. The test vectors are generated using a netlist of the circuit design. The test vectors are used to simulate operation of the circuit, and responses to the simulation are detected and used to identify design-specific circuit characteristics and a boundary scan test program is generated using the design-specific circuit characteristics.